



μ PD42S17405, 4217405

16 M-BIT DYNAMIC RAM
4 M-WORD BY 4-BIT, EDO

Description

The μ PD42S17405, 4217405 are 4,194,304 words by 4 bits CMOS dynamic RAMs with optional EDO.

EDO is a kind of the page mode and is useful for the read operation.

Besides, the μ PD42S17405 can execute $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh.

The μ PD42S17405, 4217405 are packaged in 26-pin plastic TSOP (II) and 26-pin plastic SOJ.

Features

- EDO (Hyper page mode)
- 4,194,304 words by 4 bits organization
- Single +5.0 V $\pm 10\%$ power supply
- Fast access and cycle time

Part number	Power consumption Active (MAX.)	Access time (MAX.)	R/W cycle time (MIN.)	EDO (Hyper page mode) cycle time (MIN.)
μ PD42S17405-50, 4217405-50	660 mW	50 ns	84 ns	20 ns
μ PD42S17405-60, 4217405-60	605 mW	60 ns	104 ns	25 ns
μ PD42S17405-70, 4217405-70	550 mW	70 ns	124 ns	30 ns

- μ PD42S17405 can execute $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh

Part number	Refresh cycle	Refresh	Power consumption at standby (MAX.)
μ PD42S17405	2,048 cycles/128 ms	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh RAS only refresh Hidden refresh	1.4 mW (CMOS level input)
μ PD4217405	2,048 cycles/32 ms	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh RAS only refresh Hidden refresh	5.5 mW (CMOS level input)

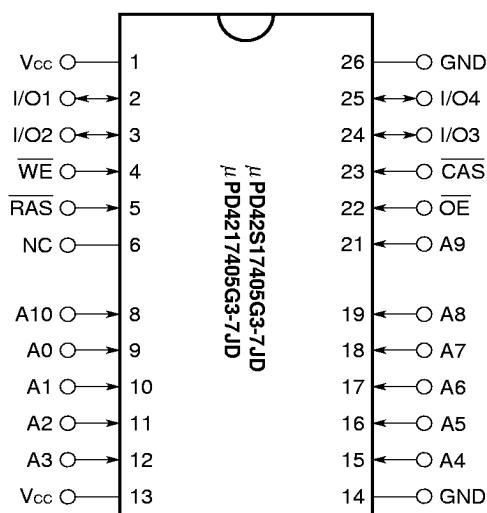
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Ordering Information

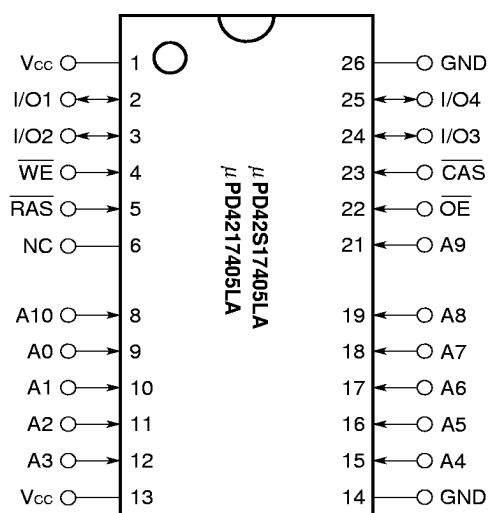
Part number	Access time (MAX.)	Package	Refresh
μ PD42S17405G3-50-7JD	50 ns	26-pin plastic TSOP (II) (300 mil)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh $\overline{\text{RAS}}$ only refresh Hidden refresh
μ PD42S17405G3-60-7JD	60 ns		
μ PD42S17405G3-70-7JD	70 ns		
μ PD42S17405LA-50	50 ns	26-pin plastic SOJ (300 mil)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh $\overline{\text{RAS}}$ only refresh Hidden refresh
μ PD42S17405LA-60	60 ns		
μ PD42S17405LA-70	70 ns		
μ PD4217405G3-50-7JD	50 ns	26-pin plastic TSOP (II) (300 mil)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh $\overline{\text{RAS}}$ only refresh Hidden refresh
μ PD4217405G3-60-7JD	60 ns		
μ PD4217405G3-70-7JD	70 ns		
μ PD4217405LA-50	50 ns	26-pin plastic SOJ (300 mil)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh $\overline{\text{RAS}}$ only refresh Hidden refresh
μ PD4217405LA-60	60 ns		
μ PD4217405LA-70	70 ns		

Pin Configurations (Marking Side)

26-pin Plastic TSOP (II) (300 mil)



26-pin Plastic SOJ (300 mil)



A0 to A10 : Address Inputs

I/O1 to I/O4: Data Inputs/Outputs

RAS : Row Address Strobe

CAS : Column Address Strobe

WE : Write Enable

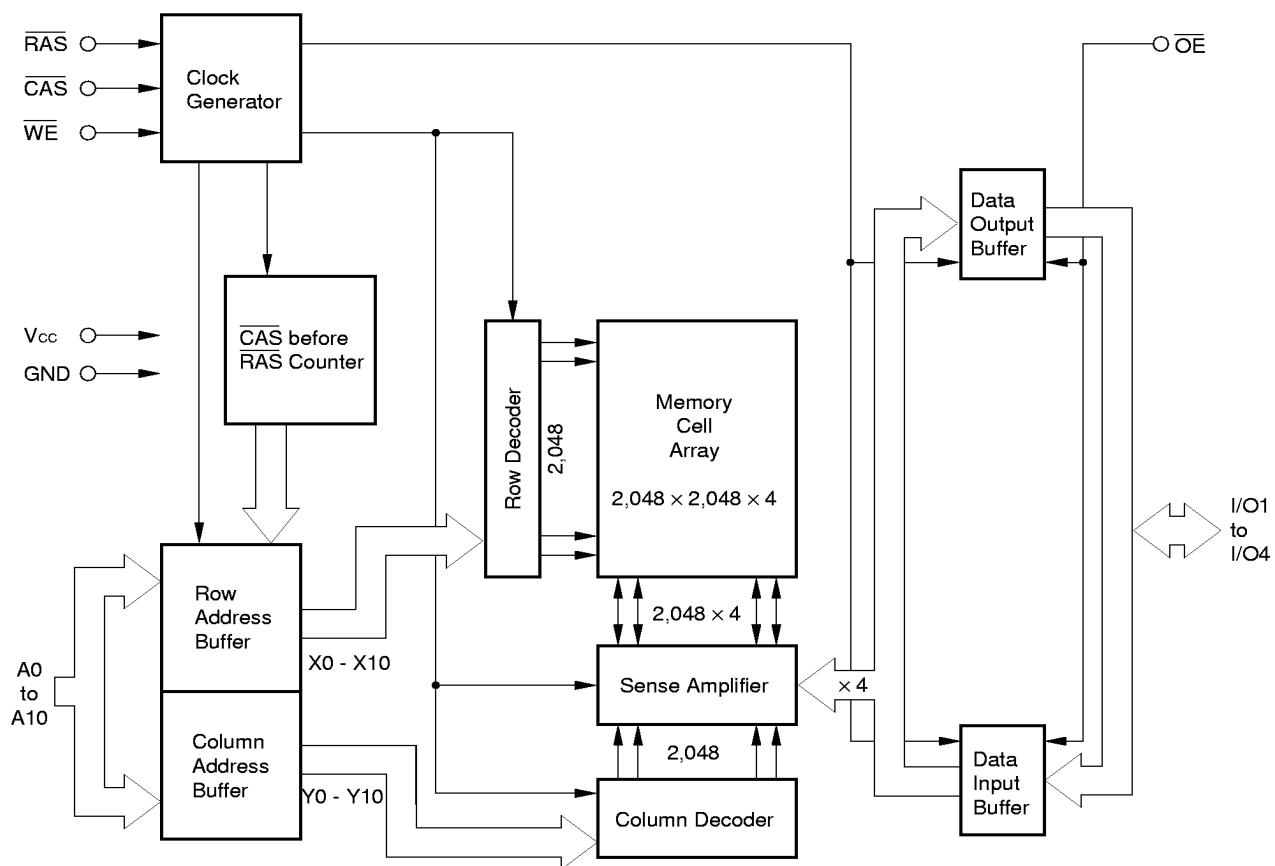
OE : Output Enable

Vcc : Power Supply

GND : Ground

NC : No Connection

Block Diagram



Input/Output Pin Functions

The μ PD42S17405, 4217405 have input pins $\overline{\text{RAS}}$, $\overline{\text{CAS}}$, $\overline{\text{WE}}$, $\overline{\text{OE}}$, A0 to A10 and input/output pins I/O1 to I/O4.

Pin name	Input/Output	Function
RAS (Row address strobe)	Input	$\overline{\text{RAS}}$ activates the sense amplifier by latching a row address and selecting a corresponding word line. It refreshes memory cell array of one line selected by the row address. It also selects the following function. <ul style="list-style-type: none">• $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh
CAS (Column address strobe)	Input	$\overline{\text{CAS}}$ activates data input/output circuit by latching column address and selecting a digit line connected with the sense amplifier.
A0 to A10 (Address inputs)	Input	Address bus. Input total 22-bit of address signal, upper 11-bit and lower 11-bit in sequence (address multiplex method). Therefore, one word is selected from 4,194,304-word by 4-bit memory cell array. In actual operation, latch row address by specifying row address and activating RAS. Then, switch the address bus to column address and activate $\overline{\text{CAS}}$. Each address is taken into the device when $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ are activated. Therefore, the address input setup time (t_{ASR} , t_{ASC}) and hold time (t_{RAH} , t_{CAH}) are specified for the activation of RAS and CAS.
$\overline{\text{WE}}$ (Write enable)	Input	Write control signal. Write operation is executed by activating $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and $\overline{\text{WE}}$.
$\overline{\text{OE}}$ (Output enable)	Input	Read control signal. Read operation can be executed by activating $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and $\overline{\text{OE}}$. If $\overline{\text{WE}}$ is activated during read operation, $\overline{\text{OE}}$ is to be ineffective in the device. Therefore, read operation cannot be executed.
I/O1 to I/O4 (Data inputs/outputs)	Input/Output	4-bit data bus. I/O1 to I/O4 are used to input/output data.

★ Hyper Page Mode (EDO)

The hyper page mode (EDO) is a kind of page mode with enhanced features. The two major features of the hyper page mode (EDO) are as follows.

1. Data output time is extended.

In the hyper page mode (EDO), the output data is held to the next $\overline{\text{CAS}}$ cycle's falling edge, instead of the rising edge. For this reason, valid data output time in the hyper page mode (EDO) is extended compared with the fast page mode (= data extend function). In the fast page mode, the data output time becomes shorter as the $\overline{\text{CAS}}$ cycle time becomes shorter. Therefore, in the hyper page mode (EDO), the timing margin in read cycle is larger than that of the fast page mode even if the $\overline{\text{CAS}}$ cycle time becomes shorter.

2. The $\overline{\text{CAS}}$ cycle time in the hyper page mode (EDO) is shorter than that in the fast page mode.

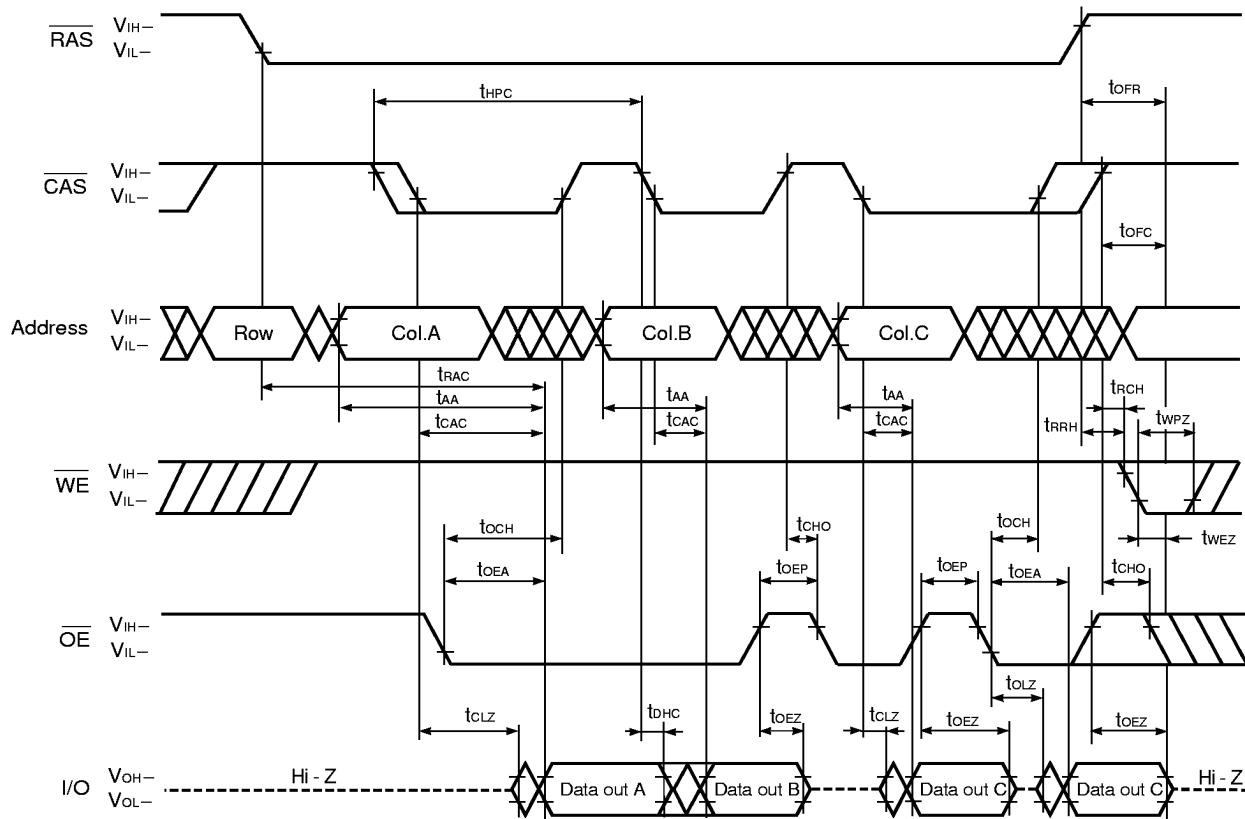
In the hyper page mode (EDO), due to the data extend function, the $\overline{\text{CAS}}$ cycle time can be shorter than in the fast page mode if the timing margin is the same.

Taking a device whose t_{RAC} is 60 ns as an example, the $\overline{\text{CAS}}$ cycle time in the fast page mode is 25 ns while that in the fast page mode is 40 ns.

In the hyper page mode (EDO), read (data out) and write (data in) cycles can be executed repeatedly during one $\overline{\text{RAS}}$ cycle. The hyper page mode (EDO) allows both read and write operations during one cycle.

The following shows a part of the hyper page mode (EDO) read cycle. Specifications to be observed are described in the next page.

Hyper Page Mode (EDO) Read Cycle



Cautions when using the hyper page mode (EDO)

1. $\overline{\text{CAS}}$ access should be used to operate t_{HPC} at the MIN. value.
2. To make I/Os to Hi-Z in read cycle, it is necessary to control $\overline{\text{RAS}}$, $\overline{\text{CAS}}$, $\overline{\text{WE}}$, $\overline{\text{OE}}$ as follows. The effective specification depends on the state of each signal.
 - (1) Both $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ are inactive (at the end of read cycle)
 $\overline{\text{WE}}$: inactive, $\overline{\text{OE}}$: active
 t_{OFC} is effective when $\overline{\text{RAS}}$ is inactivated before $\overline{\text{CAS}}$ is inactivated.
 t_{OFR} is effective when $\overline{\text{CAS}}$ is inactivated before $\overline{\text{RAS}}$ is inactivated.
The slower of t_{OFC} and t_{OFR} becomes effective.
 - (2) Both $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ are active or either $\overline{\text{RAS}}$ or $\overline{\text{CAS}}$ is active (in read cycle)
 $\overline{\text{WE}}$, $\overline{\text{OE}}$: inactive t_{OEZ} is effective.
Both $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ are inactive or $\overline{\text{RAS}}$ is active and $\overline{\text{CAS}}$ is inactive (at the end of read cycle)
 $\overline{\text{WE}}$, $\overline{\text{OE}}$: active and either t_{RRH} or t_{RCH} must be met t_{WEZ} and t_{WPZ} are effective.
The faster of t_{OEZ} and t_{WEZ} becomes effective.
The faster of (1) and (2) becomes effective.
3. In read cycle, the effective specification depends on the state of $\overline{\text{CAS}}$ signal when controlling data output with the $\overline{\text{OE}}$ signal.
 - (1) $\overline{\text{CAS}}$: inactive, $\overline{\text{OE}}$: active t_{CHO} is effective.
 - (2) $\overline{\text{CAS}}$, $\overline{\text{OE}}$: active t_{OCH} is effective.

Electrical Specifications

- All voltages are referenced to GND.
- After power up ($V_{CC} \geq V_{CC(MIN.)}$), wait more than $100 \mu s$ (\overline{RAS} , \overline{CAS} inactive) and then, execute eight \overline{CAS} before \overline{RAS} or \overline{RAS} only refresh cycles as dummy cycles to initialize internal circuit.

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Voltage on any pin relative to GND	V_T		-1.0 to +7.0	V
Supply voltage	V_{CC}		-1.0 to +7.0	V
Output current	I_O		50	mA
Power dissipation	P_D		1	W
Operating ambient temperature	T_A		0 to +70	°C
Storage temperature	T_{STG}		-55 to +125	°C

Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Supply voltage	V_{CC}		4.5	5.0	5.5	V
High level input voltage	V_{IH}		2.4		$V_{CC} + 1.0$	V
Low level input voltage	V_{IL}		-1.0		+0.8	V
Operating ambient temperature	T_A		0		70	°C

Capacitance ($T_A = 25^\circ C$, $f = 1 MHz$)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	C_{I1}	Address			5	pF
	C_{I2}	\overline{RAS} , \overline{CAS} , \overline{WE} , \overline{OE}			7	
Data input/output capacitance	$C_{I/O}$	I/O			7	pF

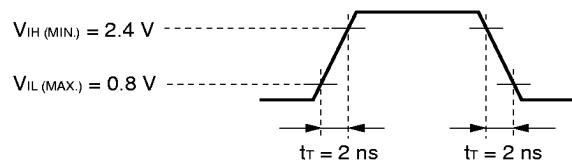
DC Characteristics (Recommended operating conditions unless otherwise noted)

Parameter		Symbol	Test condition		MIN.	MAX.	Unit	Notes
Operating current		Icc1	$\overline{\text{RAS}}, \overline{\text{CAS}}$ cycling $t_{RC} = t_{RC(\text{MIN.})}$, $I_o = 0 \text{ mA}$		$t_{\text{TRAC}} = 50 \text{ ns}$	120	mA	1, 2, 3
					$t_{\text{TRAC}} = 60 \text{ ns}$	110		
					$t_{\text{TRAC}} = 70 \text{ ns}$	100		
Standby current	μ PD42S17405	Icc2	$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{IH(\text{MIN.})}$, $I_o = 0 \text{ mA}$			2.0	mA	
			$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{CC} - 0.2 \text{ V}$, $I_o = 0 \text{ mA}$			0.25		
	μ PD4217405		$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{IH(\text{MIN.})}$, $I_o = 0 \text{ mA}$			2.0		
			$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{CC} - 0.2 \text{ V}$, $I_o = 0 \text{ mA}$			1.0		
RAS only refresh current		Icc3	$\overline{\text{RAS}}$ cycling, $\overline{\text{CAS}} \geq V_{IH(\text{MIN.})}$ $t_{RC} = t_{RC(\text{MIN.})}$, $I_o = 0 \text{ mA}$		$t_{\text{TRAC}} = 50 \text{ ns}$	120	mA	1, 2, 3, 4
					$t_{\text{TRAC}} = 60 \text{ ns}$	110		
					$t_{\text{TRAC}} = 70 \text{ ns}$	100		
Operating current (Hyper page mode (EDO))		Icc4	$\overline{\text{RAS}} \leq V_{IL(\text{MAX.})}$, $\overline{\text{CAS}}$ cycling $t_{HPC} = t_{HPC(\text{MIN.})}$, $I_o = 0 \text{ mA}$		$t_{\text{TRAC}} = 50 \text{ ns}$	100	mA	1, 2, 5
					$t_{\text{TRAC}} = 60 \text{ ns}$	90		
					$t_{\text{TRAC}} = 70 \text{ ns}$	80		
CAS before RAS refresh current		Icc5	$\overline{\text{RAS}}$ cycling $t_{RC} = t_{RC(\text{MIN.})}$, $I_o = 0 \text{ mA}$		$t_{\text{TRAC}} = 50 \text{ ns}$	120	mA	1, 2
					$t_{\text{TRAC}} = 60 \text{ ns}$	110		
					$t_{\text{TRAC}} = 70 \text{ ns}$	100		
CAS before RAS long refresh current (2,048 cycles / 128 ms, only for the μ PD42S17405)		Icc6	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh: $t_{RC} = 62.5 \mu\text{s}$ $\overline{\text{RAS}}, \overline{\text{CAS}}:$ $V_{CC} - 0.2 \text{ V} \leq V_{IH} \leq V_{IH(\text{MAX.})}$ $0 \text{ V} \leq V_{IL} \leq 0.2 \text{ V}$ Standby: $\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{CC} - 0.2 \text{ V}$ Address: V_{IH} or V_{IL} $\overline{WE}, \overline{OE}: V_{IH}$ $I_o = 0 \text{ mA}$		$t_{\text{TRAS}} \leq 300 \text{ ns}$	400	μA	1, 2
					$t_{\text{TRAS}} \leq 1 \mu\text{s}$	500	μA	1, 2
$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh current (only for the μ PD42S17405)		Icc7	$\overline{\text{RAS}}, \overline{\text{CAS}}:$ $t_{\text{TRASS}} = 5 \text{ ms}$ $V_{CC} - 0.2 \text{ V} \leq V_{IH} \leq V_{IH(\text{MAX.})}$ $0 \text{ V} \leq V_{IL} \leq 0.2 \text{ V}$ $I_o = 0 \text{ mA}$			250	μA	2
Input leakage current	$I_{I(L)}$		$V_I = 0$ to 5.5 V All other pins not under test = 0 V		-10	+10	μA	
Output leakage current	$I_{o(L)}$		$V_O = 0$ to 5.5 V Output is disabled (Hi-Z)		-10	+10	μA	
High level output voltage	V_{OH}		$I_o = -5.0 \text{ mA}$		2.4		V	
Low level output voltage	V_{OL}		$I_o = +4.2 \text{ mA}$			0.4	V	

- Notes**
1. Icc1, Icc3, Icc4, Icc5 and Icc6 depend on cycle rates (t_{RC} and t_{HPC}).
 2. Specified values are obtained with outputs unloaded.
 3. Icc1 and Icc3 are measured assuming that address can be changed once or less during $\overline{\text{RAS}} \leq V_{IL(\text{MAX.})}$ and $\overline{\text{CAS}} \geq V_{IH(\text{MIN.})}$.
 4. Icc3 is measured assuming that all column address inputs are held at either high or low.
 5. Icc4 is measured assuming that all column address inputs are switched only once during each hyper page (EDO) cycle.

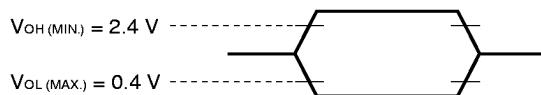
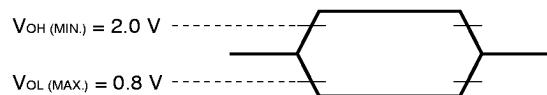
AC Characteristics (Recommended Operating Conditions unless otherwise noted)**AC Characteristics Test Conditions**

(1) Input timing specification

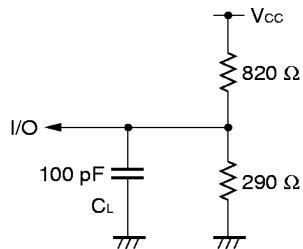


★ (2) Output timing specification

- μ PD42S17405-50, 4217405-50
- μ PD42S17405-60, 4217405-60
- μ PD42S17405-70, 4217405-70



(3) Output loading conditions



Common to Read, Write, Read Modify Write Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read / Write cycle time	t _{RC}	84	—	104	—	124	—	ns	
RAS precharge time	t _{RP}	30	—	40	—	50	—	ns	
CAS precharge time	t _{CPN}	8	—	10	—	10	—	ns	
RAS pulse width	t _{RA}	50	10,000	60	10,000	70	10,000	ns	1
CAS pulse width	t _{CA}	8	10,000	10	10,000	12	10,000	ns	
RAS hold time	t _{RSH}	10	—	10	—	12	—	ns	
CAS hold time	t _{CSH}	38	—	40	—	50	—	ns	
RAS to CAS delay time	t _{RCRD}	11	37	14	45	14	52	ns	2
RAS to column address delay time	t _{RAD}	9	25	12	30	12	35	ns	2
CAS to RAS precharge time	t _{CRP}	5	—	5	—	5	—	ns	3
Row address setup time	t _{ASR}	0	—	0	—	0	—	ns	
Row address hold time	t _{RAH}	7	—	10	—	10	—	ns	
Column address setup time	t _{ASC}	0	—	0	—	0	—	ns	
Column address hold time	t _{CAH}	7	—	10	—	12	—	ns	
OE lead time referenced to RAS	t _{OES}	0	—	0	—	0	—	ns	
CAS to data setup time	t _{CLZ}	0	—	0	—	0	—	ns	
OE to data setup time	t _{OLZ}	0	—	0	—	0	—	ns	
OE to data delay time	t _{OED}	10	—	13	—	15	—	ns	
Transition time (rise and fall)	t _T	1	50	1	50	1	50	ns	
Refresh time	μ PD42S17405	t _{REF}	—	128	—	128	—	128	ms
	μ PD4217405		—	32	—	32	—	32	

Notes 1. In CAS before RAS refresh cycles, t_{RA}(MAX.) is 100 μ s.

If 10 μ s < t_{RA} < 100 μ s, RAS precharge time for CAS before RAS self refresh (t_{RP}) is applied.

2. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from RAS
t _{RA} ≤ t _{RD} (MAX.) and t _{RCRD} ≤ t _{RC} (MAX.)	t _{RAC} (MAX.)	t _{RAC} (MAX.)
t _{RA} > t _{RD} (MAX.) and t _{RCRD} ≤ t _{RC} (MAX.)	t _{AA} (MAX.)	t _{RD} + t _{AA} (MAX.)
t _{RCRD} > t _{RC} (MAX.)	t _{CAC} (MAX.)	t _{RCRD} + t _{CAC} (MAX.)

t_{RD} (MAX.) and t_{RC} (MAX.) are specified as reference points only ; they are not restrictive operating parameters. They are used to determine which access time (t_{RAC}, t_{AA} or t_{CAC}) is to be used for finding out when output data will be available. Therefore, the input conditions t_{RD} ≥ t_{RA} (MAX.) and t_{RCRD} ≥ t_{RC} (MAX.) will not cause any operation problems.

3. t_{CRP} (MIN.) requirement is applied to RAS, CAS cycles.

4. This specification is applied only to the μ PD42S17405.

Read Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Access time from RAS	t _{RAC}	—	50	—	60	—	70	ns	1
Access time from CAS	t _{CAC}	—	13	—	15	—	18	ns	1
Access time from column address	t _{AA}	—	25	—	30	—	35	ns	1
Access time from \overline{OE}	t _{OE} A	—	13	—	15	—	18	ns	
Column address lead time referenced to RAS	t _{RL}	25	—	30	—	35	—	ns	
Read command setup time	t _{RC} S	0	—	0	—	0	—	ns	
Read command hold time referenced to RAS	t _{RRH}	0	—	0	—	0	—	ns	2
Read command hold time referenced to CAS	t _{RC} H	0	—	0	—	0	—	ns	2
Output buffer turn-off delay time from \overline{OE}	t _{OZ}	0	10	0	13	0	15	ns	3
CAS hold time to \overline{OE}	t _{CHO}	5	—	5	—	5	—	ns	4

Notes 1. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from \overline{RAS}
t _{RAD} ≤ t _{RAD} (MAX.) and t _{RCD} ≤ t _{RCD} (MAX.)	t _{RAC} (MAX.)	t _{RAC} (MAX.)
t _{RAD} > t _{RAD} (MAX.) and t _{RCD} ≤ t _{RCD} (MAX.)	t _{AA} (MAX.)	t _{RAD} + t _{AA} (MAX.)
t _{RCD} > t _{RCD} (MAX.)	t _{CAC} (MAX.)	t _{RCD} + t _{CAC} (MAX.)

t_{RAD}(MAX.) and t_{RCD}(MAX.) are specified as reference points only; they are not restrictive operating parameters. They are used to determine which access time (t_{RAC}, t_{AA} or t_{CAC}) is to be used for finding out when output data will be available. Therefore, the input conditions t_{RAD} ≥ t_{RAD} (MAX.) and t_{RCD} ≥ t_{RCD} (MAX.) will not cause any operation problems.

2. Either t_{RC}H (MIN.) or t_{RRH} (MIN.) should be met in read cycles.
3. t_{OZ}(MAX.) defines the time when the output achieves the condition of Hi-Z and is not referenced to V_{OH} or V_{OL}.
4. WE: inactive (in read cycle)
CAS: inactive, \overline{OE} : active t_{CHO} is effective.
CAS, \overline{OE} : active t_{CHO} is effective.

★ ★ Write Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
WE hold time referenced to CAS	t _{WCH}	7	—	10	—	10	—	ns	1
WE pulse width	t _{WP}	8	—	10	—	10	—	ns	1
WE lead time referenced to RAS	t _{RWL}	10	—	10	—	12	—	ns	
WE lead time referenced to CAS	t _{CWL}	8	—	10	—	12	—	ns	
WE setup time	t _{WCS}	0	—	0	—	0	—	ns	2
OE hold time	t _{OEH}	0	—	0	—	0	—	ns	
Data-in setup time	t _{DS}	0	—	0	—	0	—	ns	3
Data-in hold time	t _{DH}	7	—	10	—	10	—	ns	3

- Notes**
1. t_{WP} (MIN.) is applied to late write cycles or read modify write cycles. In early write cycles, t_{WCH} (MIN.) should be met.
 2. If t_{WCS} ≥ t_{WCS} (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle.
 3. t_{DS} (MIN.) and t_{DH} (MIN.) are referenced to the CAS falling edge in early write cycles. In late write cycles and read modify write cycles, they are referenced to the WE falling edge.

Read Modify Write Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read modify write cycle time	t _{RWC}	107	—	133	—	157	—	ns	
RAS to WE delay time	t _{RWD}	64	—	77	—	89	—	ns	1
CAS to WE delay time	t _{CWD}	27	—	32	—	37	—	ns	1
Column address to WE delay time	t _{AWD}	39	—	47	—	54	—	ns	1

- Note**
1. If t_{WCS} ≥ t_{WCS} (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If t_{RWD} ≥ t_{RWD} (MIN.), t_{CWD} ≥ t_{CWD} (MIN.), t_{AWD} ≥ t_{AWD} (MIN.) and t_{CPWD} ≥ t_{CPWD} (MIN.), the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

Hyper Page Mode (EDO)

Parameter	Symbol	t _{TRAC} = 50 ns		t _{TRAC} = 60 ns		t _{TRAC} = 70 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read / Write cycle time	t _{HPC}	20	—	25	—	30	—	ns	1
RAS pulse width	t _{RASP}	50	125,000	60	125,000	70	125,000	ns	
★ CAS pulse width	t _{HCAS}	8	10,000	10	10,000	12	10,000	ns	
★ CAS precharge time	t _{CP}	8	—	10	—	10	—	ns	
Access time from <u>CAS</u> precharge	t _{ACP}	—	30	—	35	—	40	ns	
CAS precharge to WE delay time	t _{CPWD}	41	—	52	—	59	—	ns	2
RAS hold time from <u>CAS</u> precharge	t _{RHCP}	30	—	35	—	40	—	ns	
Read modify write cycle time	t _{HPRWC}	52	—	66	—	75	—	ns	
Data output hold time	t _{DHC}	5	—	5	—	5	—	ns	
OE to <u>CAS</u> hold time	t _{CH}	5	—	5	—	5	—	ns	3
OE precharge time	t _{OEP}	5	—	5	—	5	—	ns	
Output buffer turn-off delay from WE	t _{WEZ}	0	10	0	13	0	15	ns	4,5
★ WE pulse width	t _{WPZ}	8	—	10	—	10	—	ns	5
Output buffer turn-off delay from RAS	t _{OFR}	0	10	0	13	0	15	ns	4,5
Output buffer turn-off delay from CAS	t _{OFC}	0	10	0	13	0	15	ns	4,5

Notes 1. t_{HPC} (MIN.) is applied to CAS access.

2. If t_{WCS} ≥ t_{WCS} (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If t_{RWD} ≥ t_{RWD} (MIN.), t_{CWD} ≥ t_{CWD} (MIN.), t_{AWD} ≥ t_{AWD} (MIN.) and t_{CPWD} ≥ t_{CPWD} (MIN.), the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

3. WE: inactive (in read cycle)

CAS: inactive, OE: active t_{CH} is effective.

CAS, OE: active t_{CH} is effective.

4. t_{OFC} (MAX.), t_{OFR} (MAX.) and t_{WEZ} (MAX.) define the time when the output achieves the conditions of Hi-Z and is not referenced to V_{OH} or V_{OL}.

5. To make I/Os to Hi-Z in read cycle, it is necessary to control RAS, CAS, WE, OE as follows. The effective specification depends on state of each signal.

- (1) Both RAS and CAS are inactive (at the end of the read cycle)

WE: inactive, OE: active

t_{OFC} is effective when RAS is inactivated before CAS is inactivated.

t_{OFR} is effective when CAS is inactivated before RAS is inactivated.

The slower of t_{OFC} and t_{OFR} becomes effective.

- (2) Both RAS and CAS are active or either RAS or CAS is active (in read cycle)

WE, OE: inactive t_{WEZ} is effective.

Both RAS and CAS are inactive or RAS is active and CAS is inactive (at the end of read cycle)

WE, OE: active and either t_{RRH} or t_{CH} must be met t_{WEZ} and t_{WPZ} are effective.

The faster of t_{WEZ} and t_{WPZ} becomes effective.

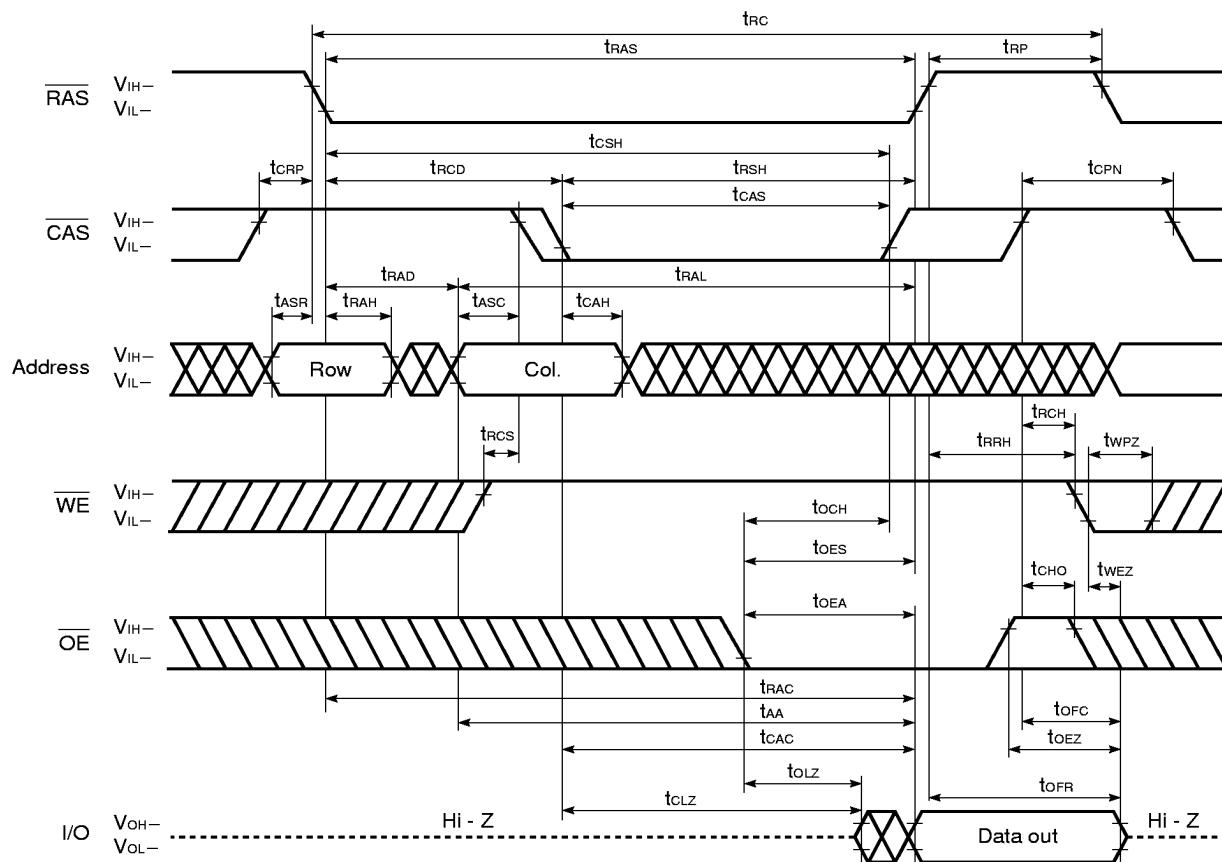
The faster of (1) and (2) becomes effective.

Refresh Cycle

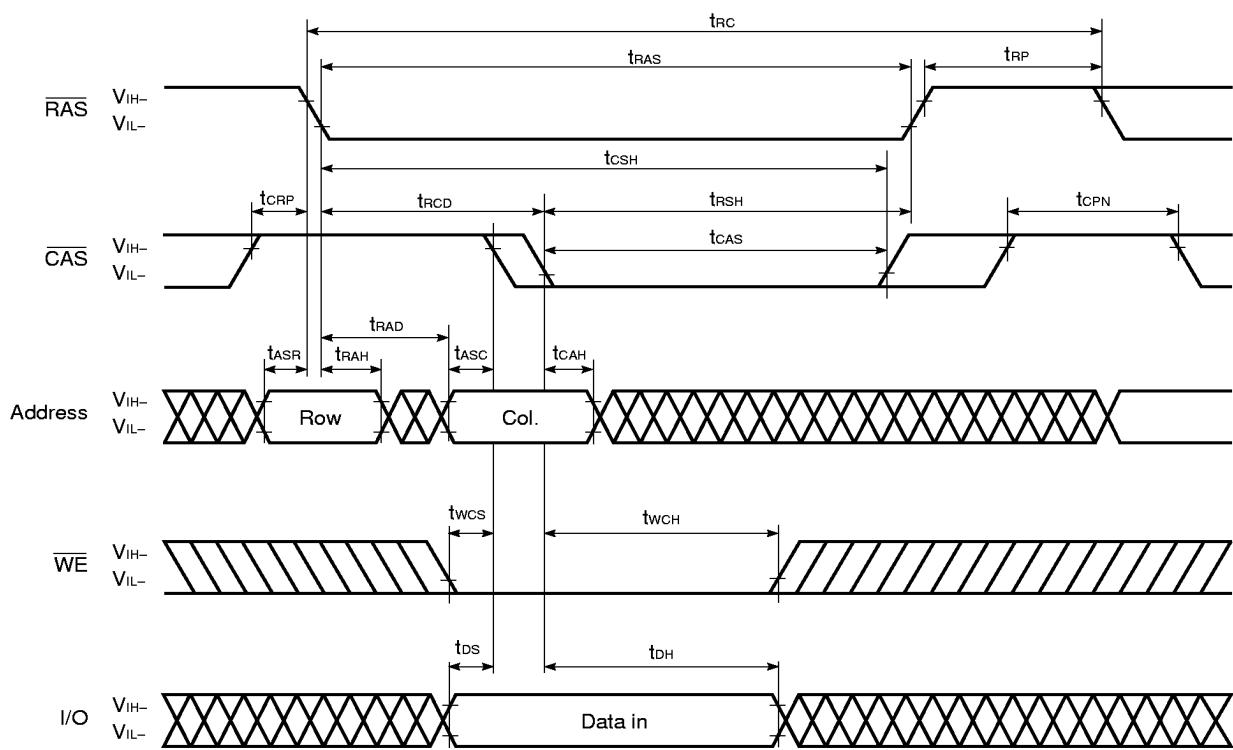
Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
CAS setup time	t _{CSR}	5	—	5	—	5	—	ns	
CAS hold time (CAS before RAS refresh)	t _{CHR}	10	—	10	—	10	—	ns	
RAS precharge CAS hold time	t _{RPC}	5	—	5	—	5	—	ns	
RAS pulse width (CAS before RAS self refresh)	t _{RASS}	100	—	100	—	100	—	μ s	1
RAS precharge time (CAS before RAS self refresh)	t _{RPS}	90	—	110	—	130	—	ns	1
CAS hold time (CAS before RAS self refresh)	t _{CHS}	—50	—	—50	—	—50	—	ns	1
WE setup time	t _{WSR}	10	—	10	—	10	—	ns	
WE hold time	t _{WHR}	15	—	15	—	15	—	ns	

Note 1. This specification is applied only to the μ PD42S17405.

Read Cycle

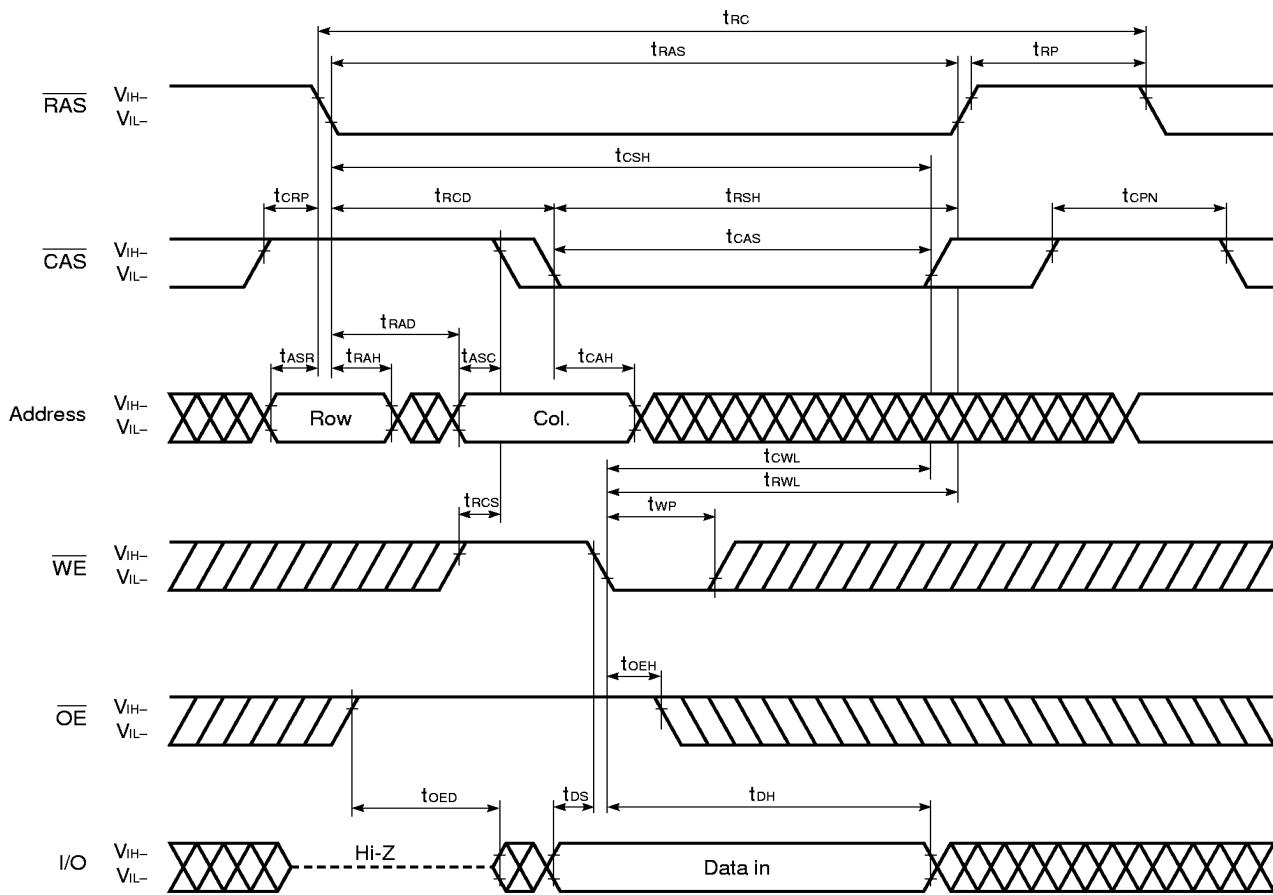


Early Write Cycle

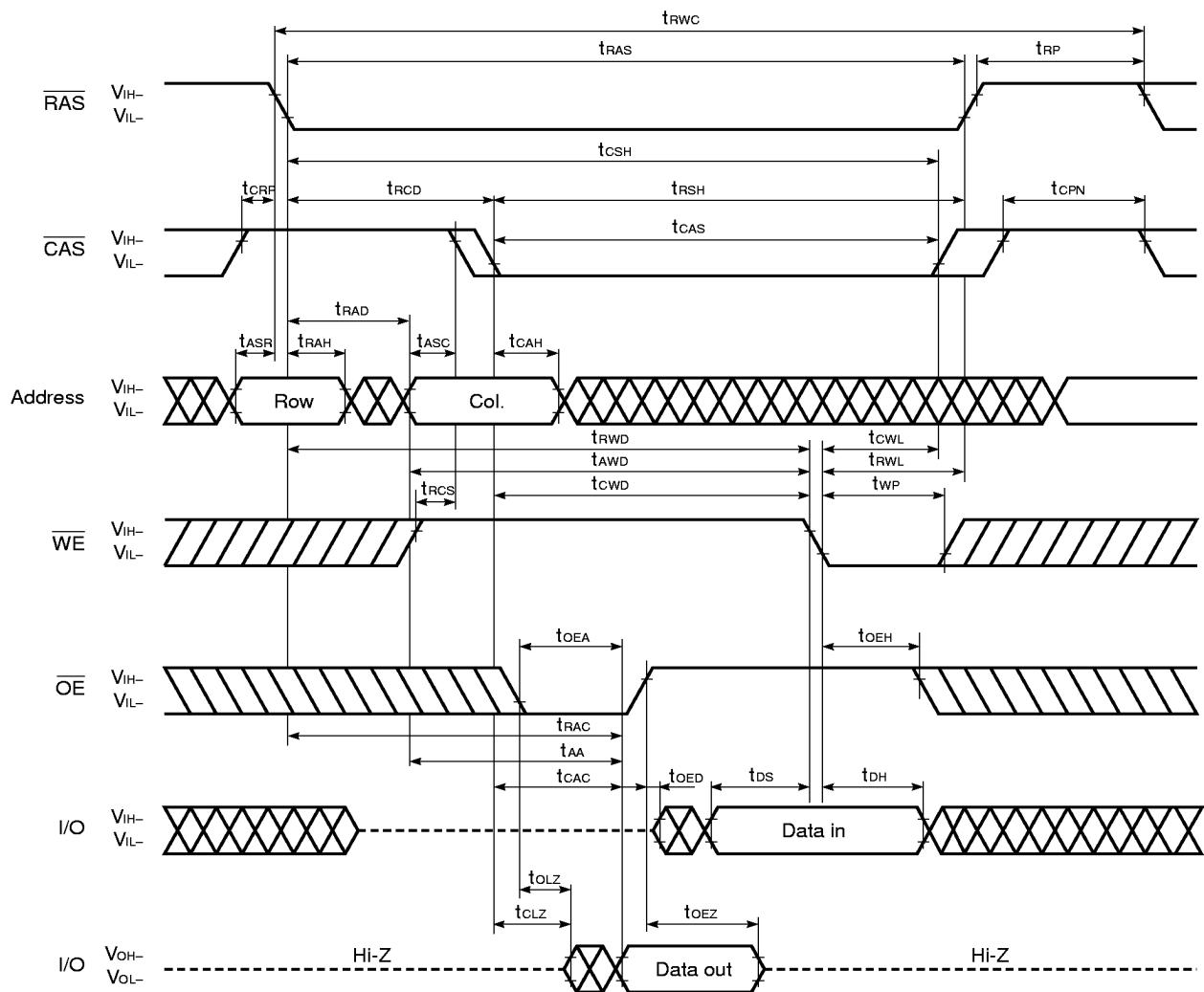


Remark \overline{OE} : Don't care

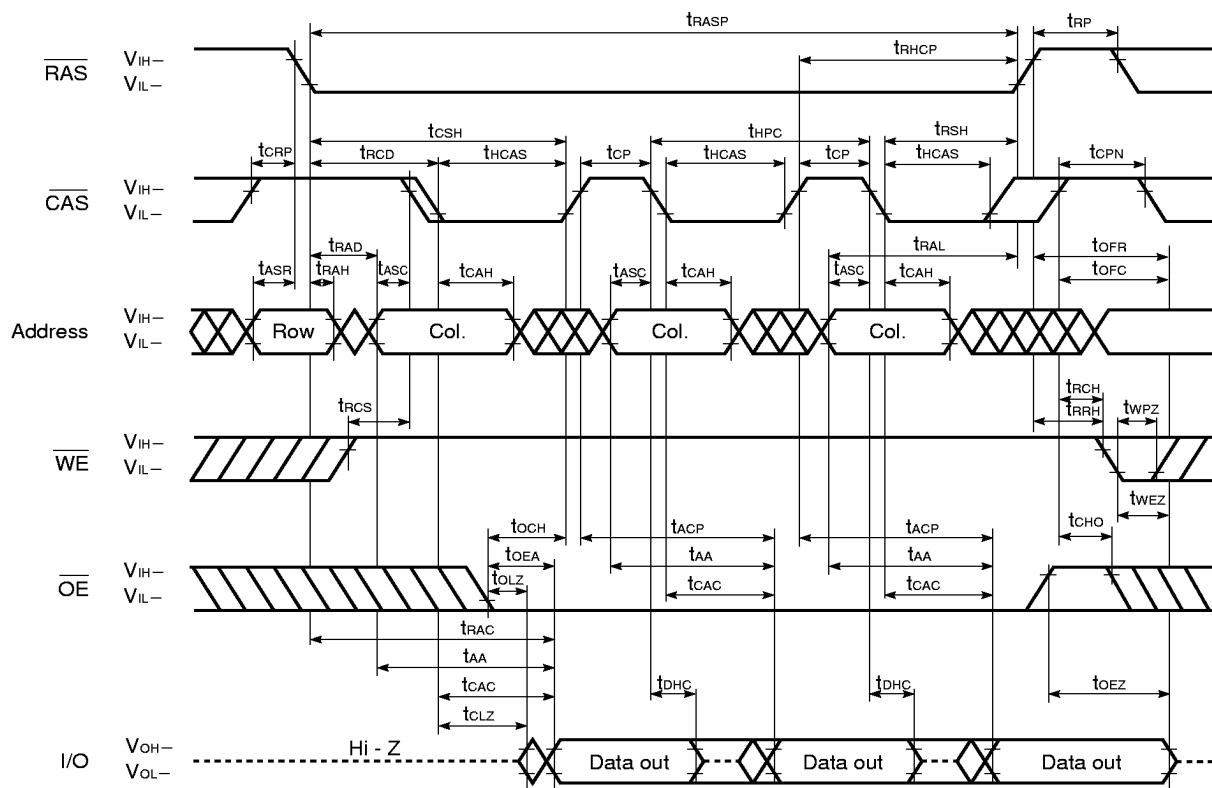
Late Write Cycle



Read Modify Write Cycle

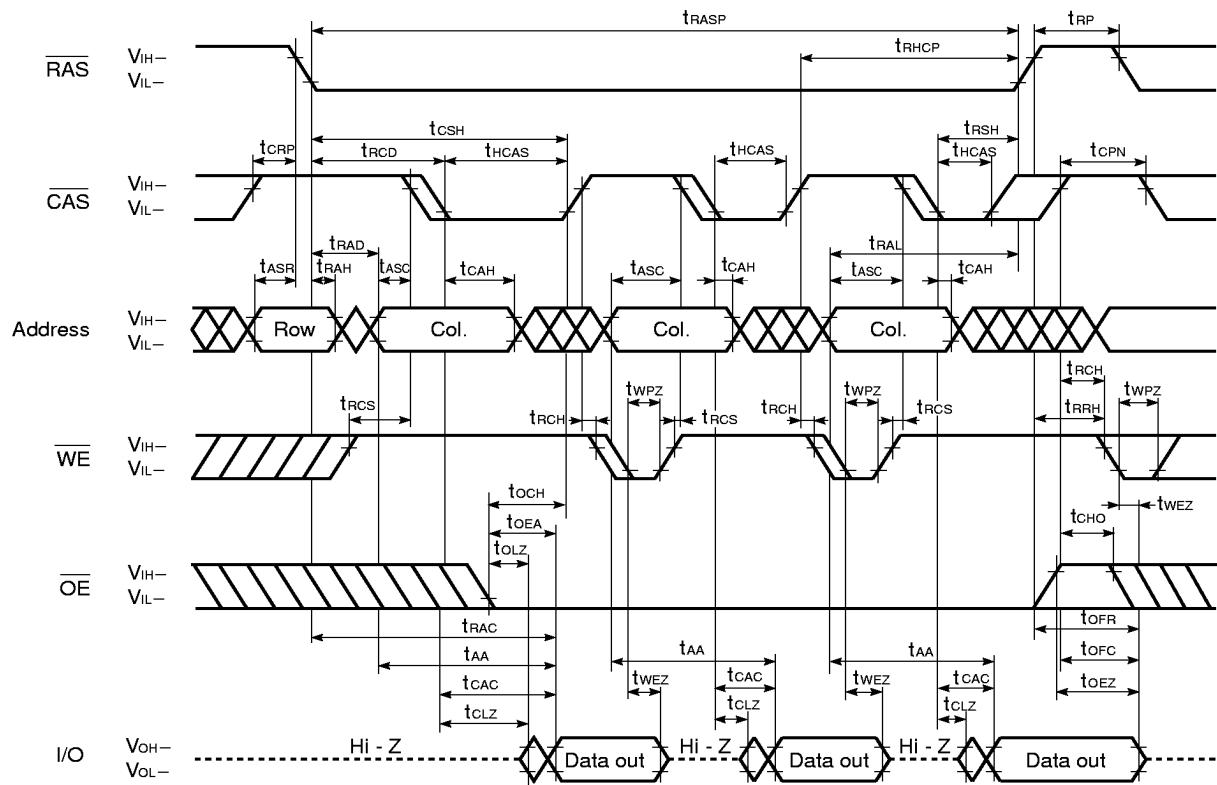


Hyper Page Mode (EDO) Read Cycle

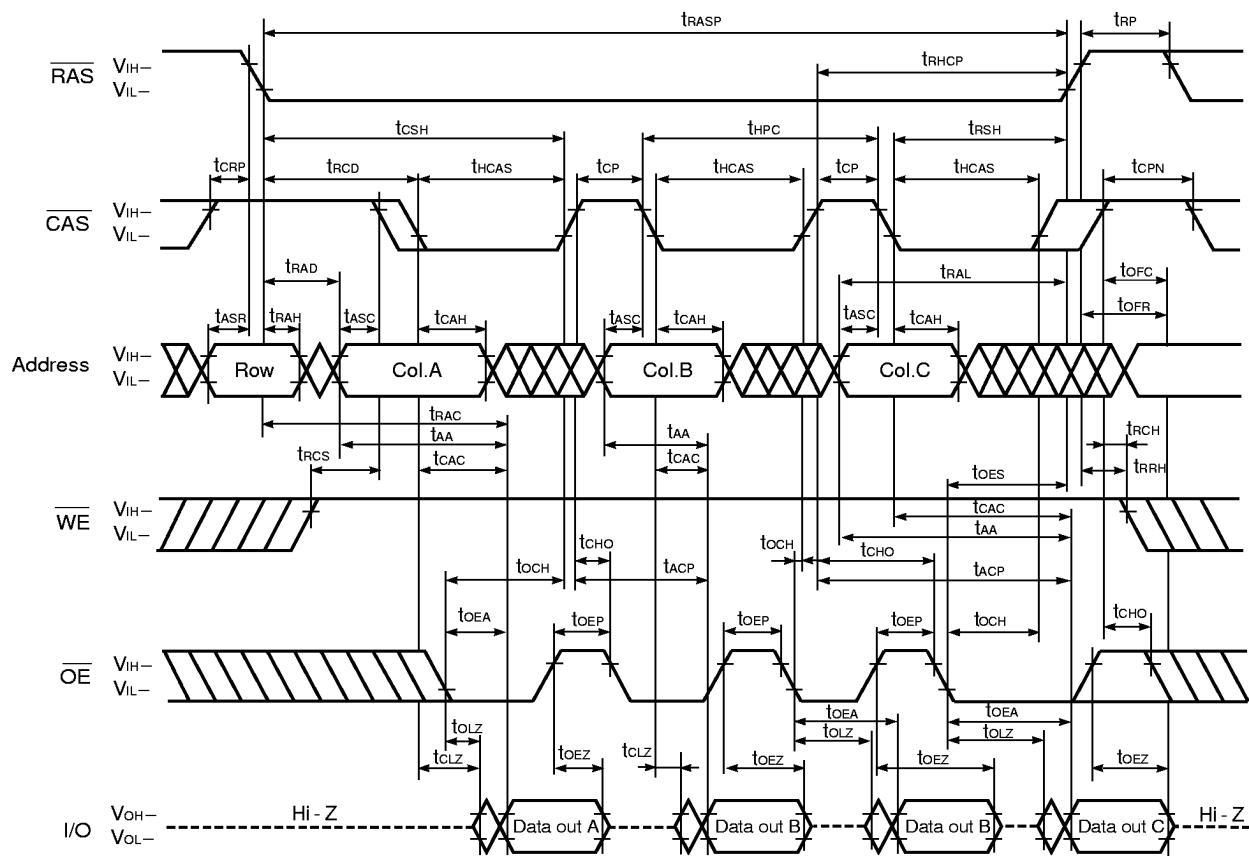


Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.

Hyper Page Mode (EDO) Read Cycle (WE Control)

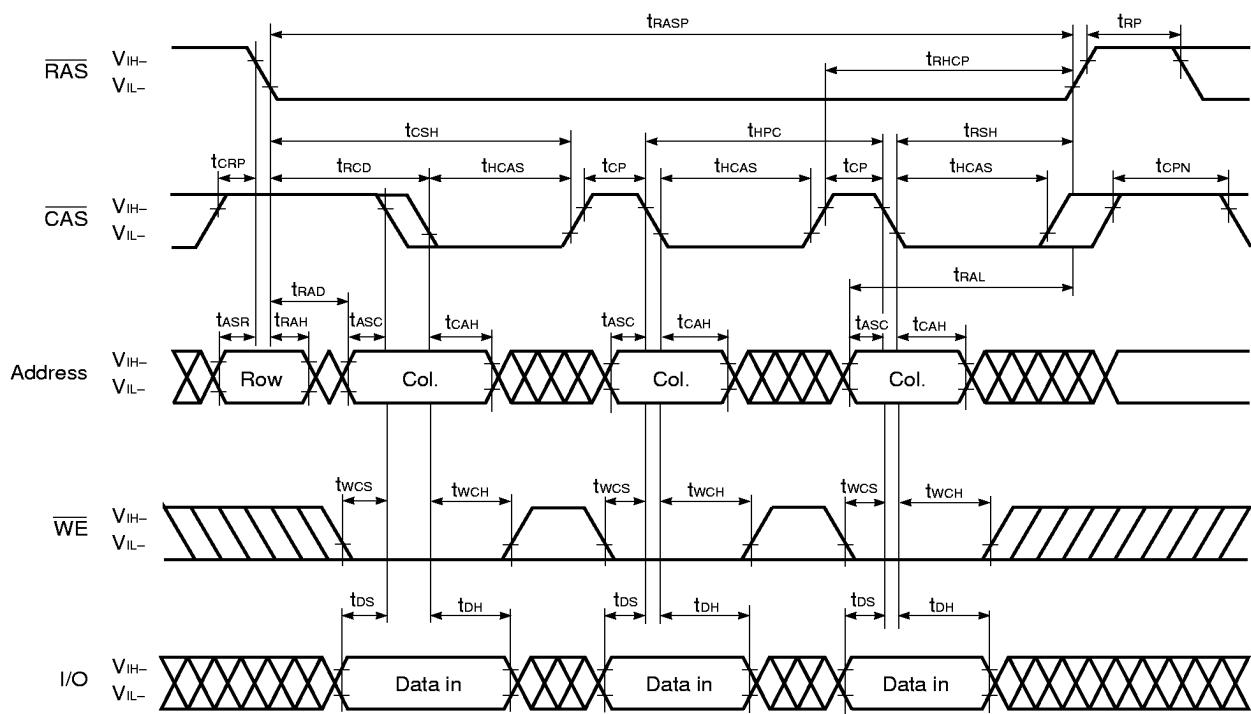


Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{\text{CAS}}$ cycles within the same $\overline{\text{RAS}}$ cycle.

Hyper Page Mode (EDO) Read Cycle (\overline{OE} Control)

Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive \overline{CAS} cycles within the same \overline{RAS} cycle.

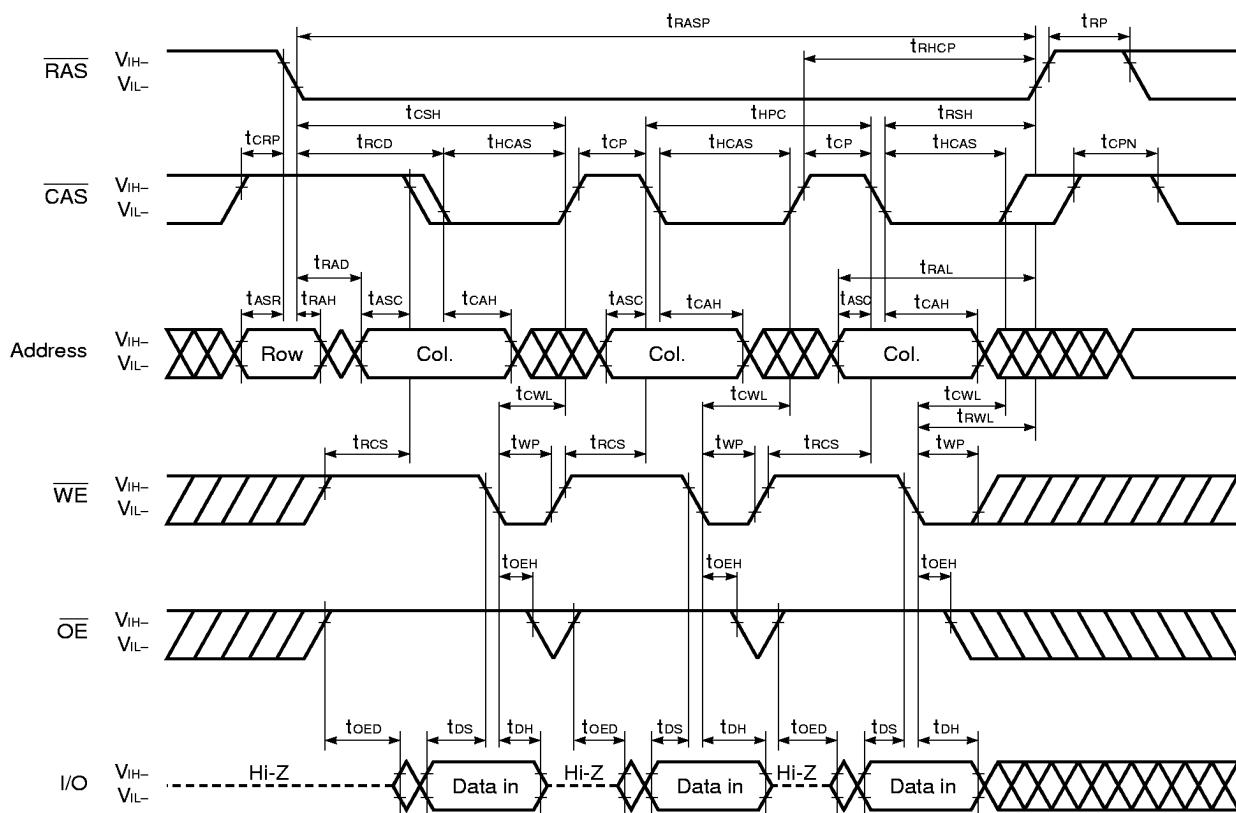
Hyper Page Mode (EDO) Early Write Cycle



Remarks 1. \overline{OE} : Don't care

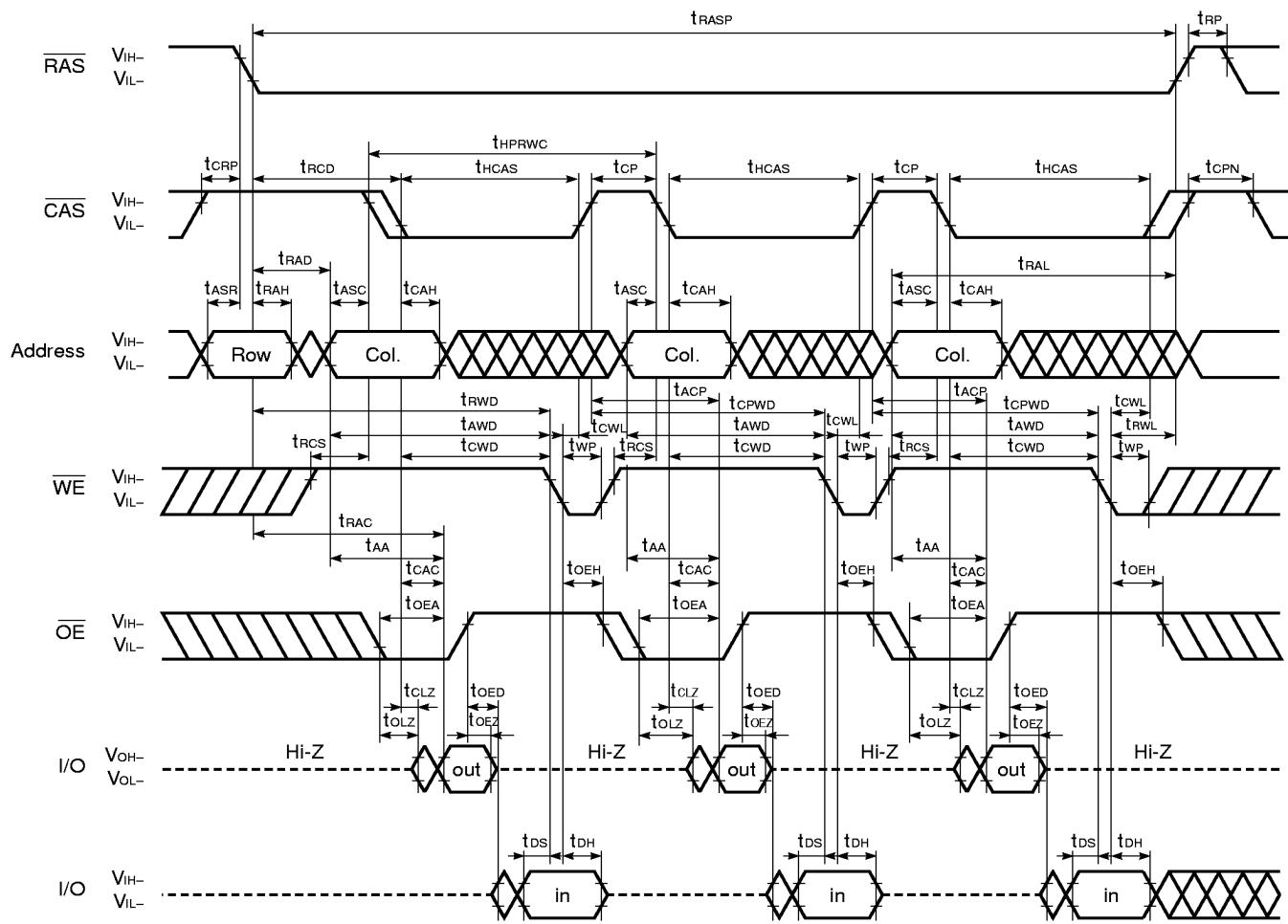
2. In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive \overline{CAS} cycles within the same \overline{RAS} cycle.

Hyper Page Mode (EDO) Late Write Cycle



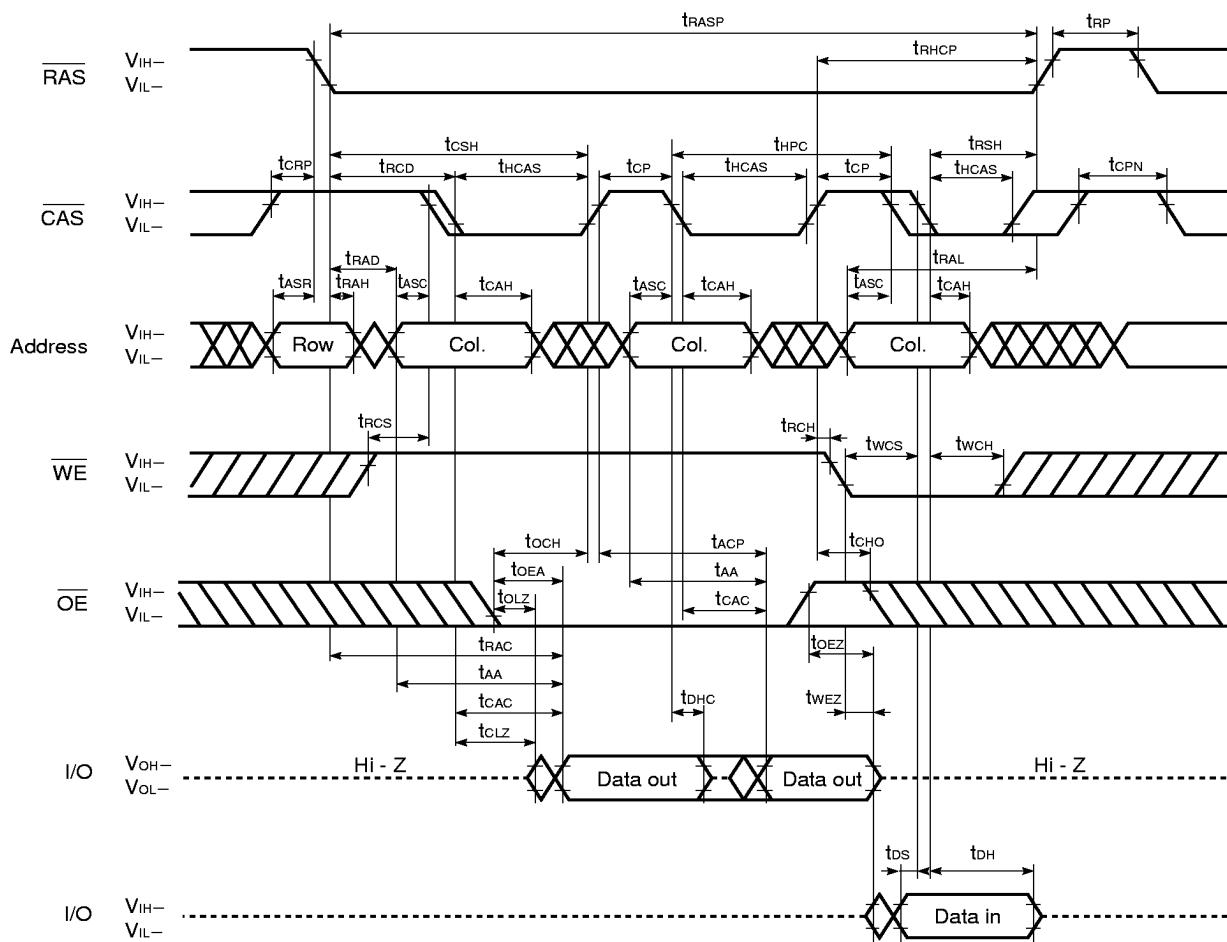
Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive $\overline{\text{CAS}}$ cycles within the same $\overline{\text{RAS}}$ cycle.

Hyper Page Mode (EDO) Read Modify Write Cycle

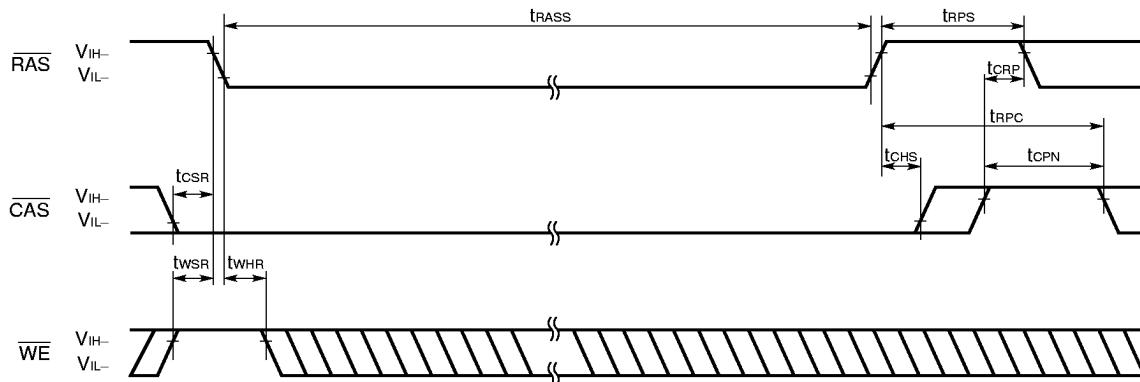


Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.

Hyper Page Mode (EDO) Read and Write Cycle



Remark In the hyper page mode (EDO), read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.

CAS Before RAS Self Refresh Cycle (Only for the μ PD42S17405)

Remark Address, \overline{OE} : Don't care I/O : Hi-Z

Cautions on Use of CAS Before RAS Self Refresh

$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh can be used independently when used in combination with distributed $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ long refresh; However, when used in combination with burst $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ long refresh or with long $\overline{\text{RAS}}$ only refresh (both distributed and burst), the following cautions must be observed.

(1) Normal Combined Use of CAS Before RAS Self Refresh and Burst CAS Before RAS Long Refresh

When $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh and burst $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ long refresh are used in combination, please perform $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh 2,048 times within a 32 ms interval just before and after setting $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh.

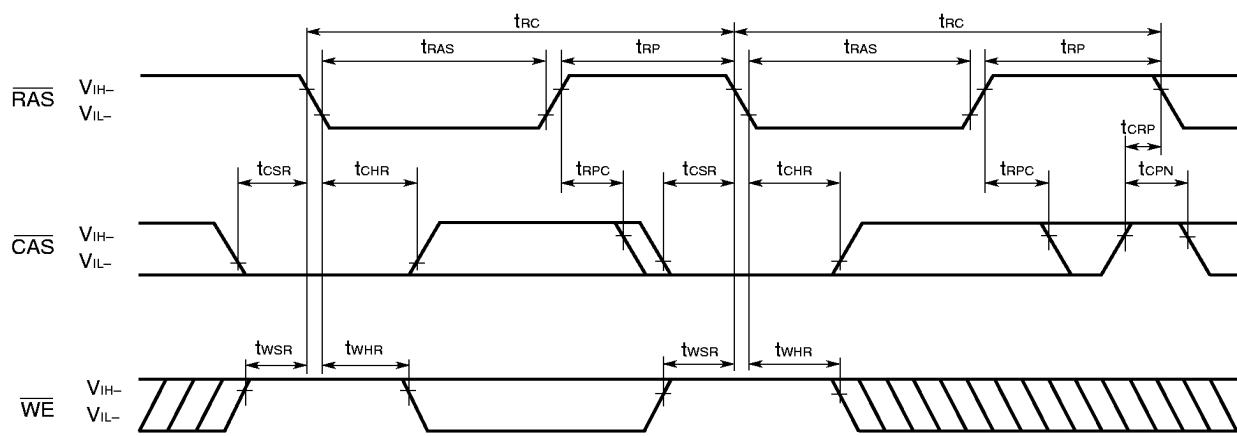
(2) Normal Combined Use of CAS Before RAS Self Refresh and Long RAS Only Refresh

When $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh and $\overline{\text{RAS}}$ only refresh are used in combination, please perform $\overline{\text{RAS}}$ only refresh 2,048 times within a 32 ms interval just before and after setting $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh.

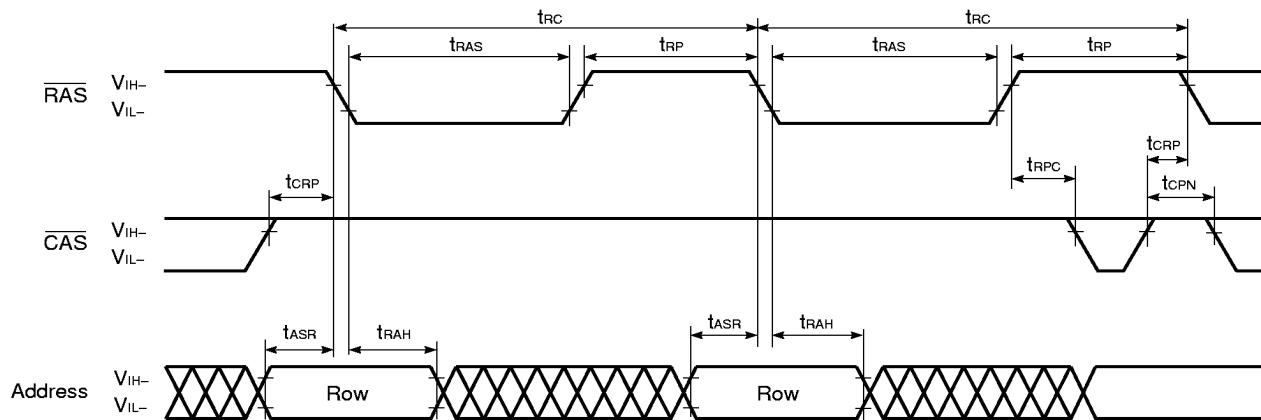
(3) If t_{RASS} (MIN.) is not satisfied at the beginning of CAS before RAS self refresh cycles ($t_{RAS} < 100 \mu\text{s}$), CAS before RAS refresh cycles will be executed one time.

If $10 \mu\text{s} < t_{RAS} < 100 \mu\text{s}$, RAS precharge time for $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ self refresh (t_{RPS}) is applied. And refresh cycles (2,048/128 ms) should be met.

For details, please refer to **How to use DRAM User's Manual**.

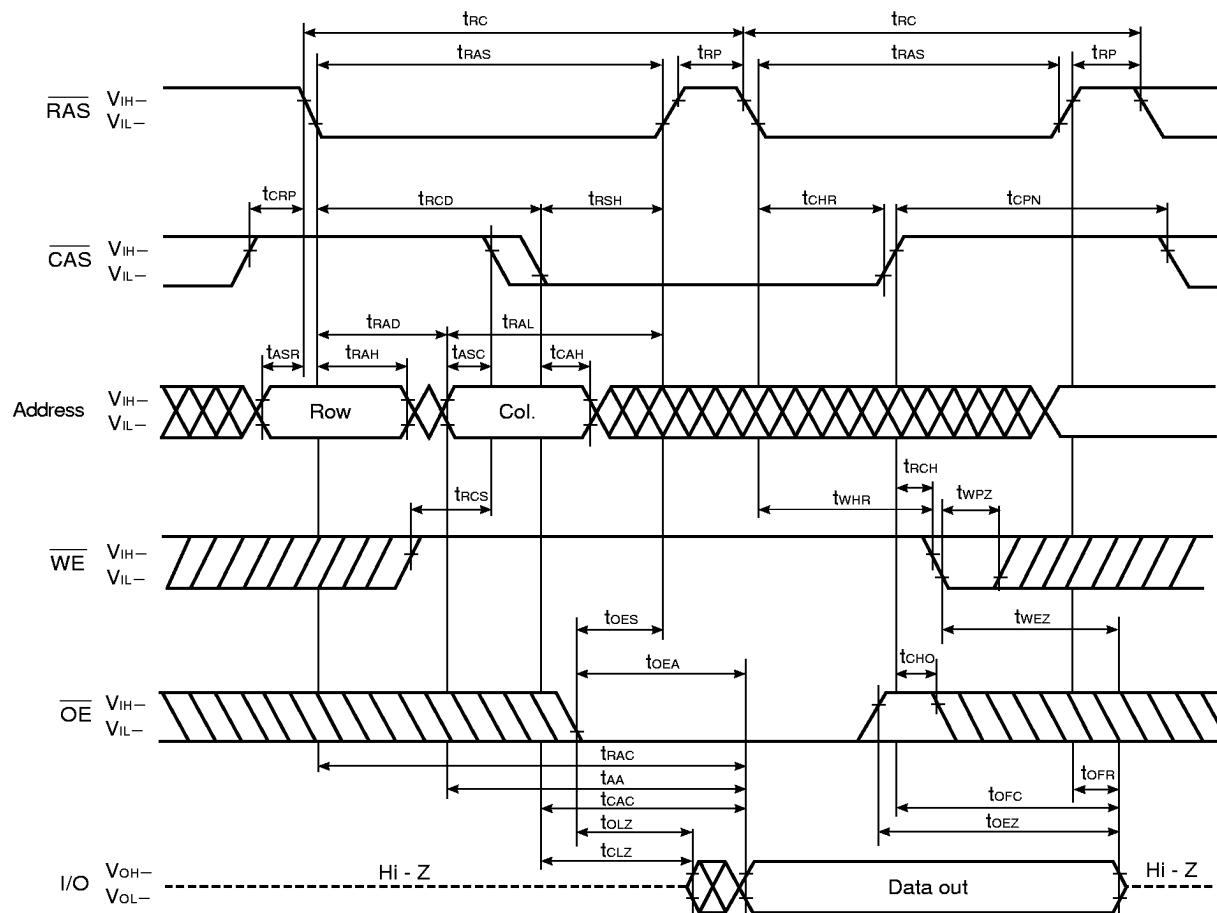
CAS Before RAS Refresh Cycle

Remark Address, $\overline{\text{OE}}$: Don't care I/O: Hi-Z

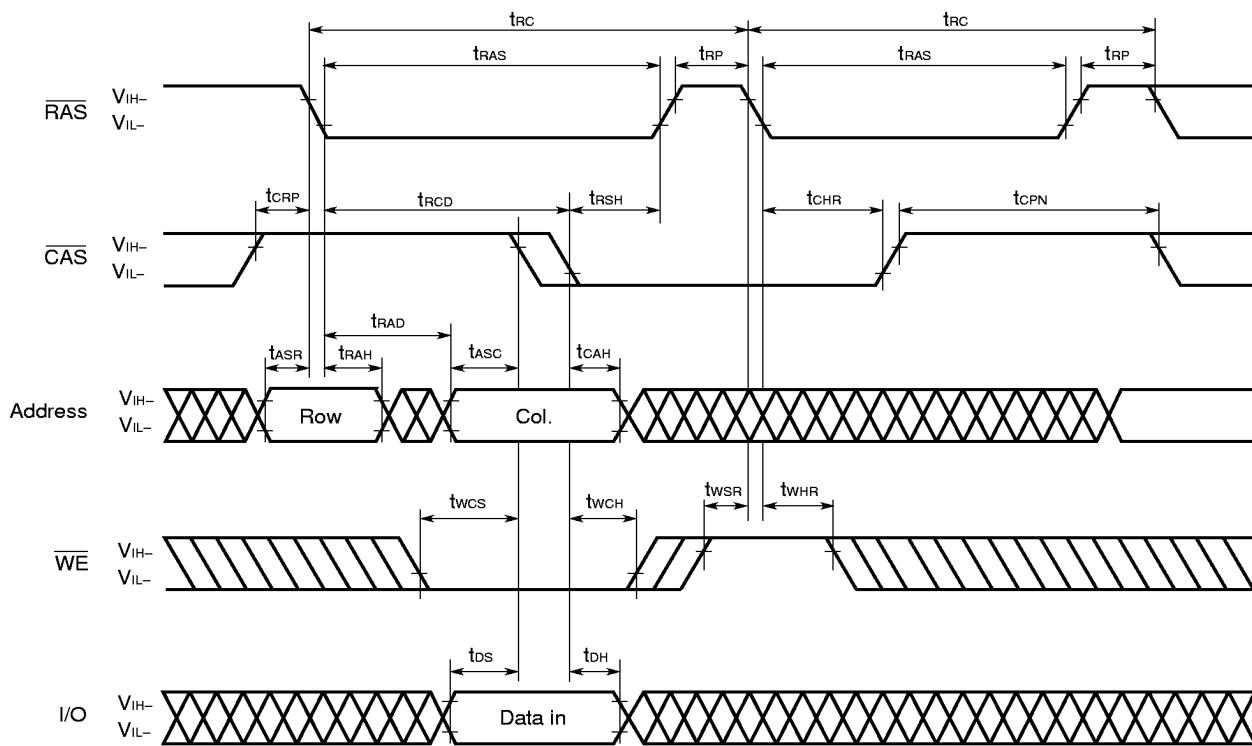
RAS Only Refresh Cycle

Remark $\overline{\text{WE}}$, $\overline{\text{OE}}$: Don't care I/O: Hi-Z

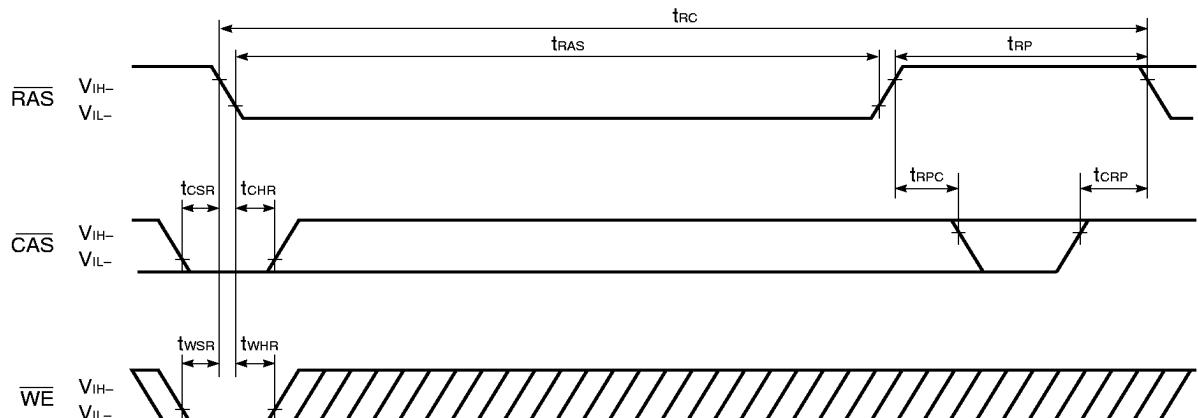
Hidden Refresh Cycle (Read)



Hidden Refresh Cycle (Write)



Remark \overline{OE} : Don't care

Test Mode Set Cycle (\overline{WE} , \overline{CAS} Before \overline{RAS} Refresh Cycle)

Remark Address, \overline{OE} : Don't care I/O: Hi-Z

Test Mode

By using the test mode, the test time can be reduced. The reason for this is that, the memory emulates the $\times 16$ -bit organization during test mode. Don't care about the input levels of the \overline{CAS} input A0, A1.

(1) Setting the mode

Executing the test mode cycle (\overline{WE} , \overline{CAS} before \overline{RAS} refresh cycle) sets the test mode.

(2) Write/read operation

When either a "0" or a "1" is written to the input pin in test mode, this data is written to 16 bits of memory cell.

Next, when the data is read from the output pin at the same address, the cell can be checked.

Output = "1": Normal write (all memory cells)

Output = "0": Abnormal write

(3) Refresh

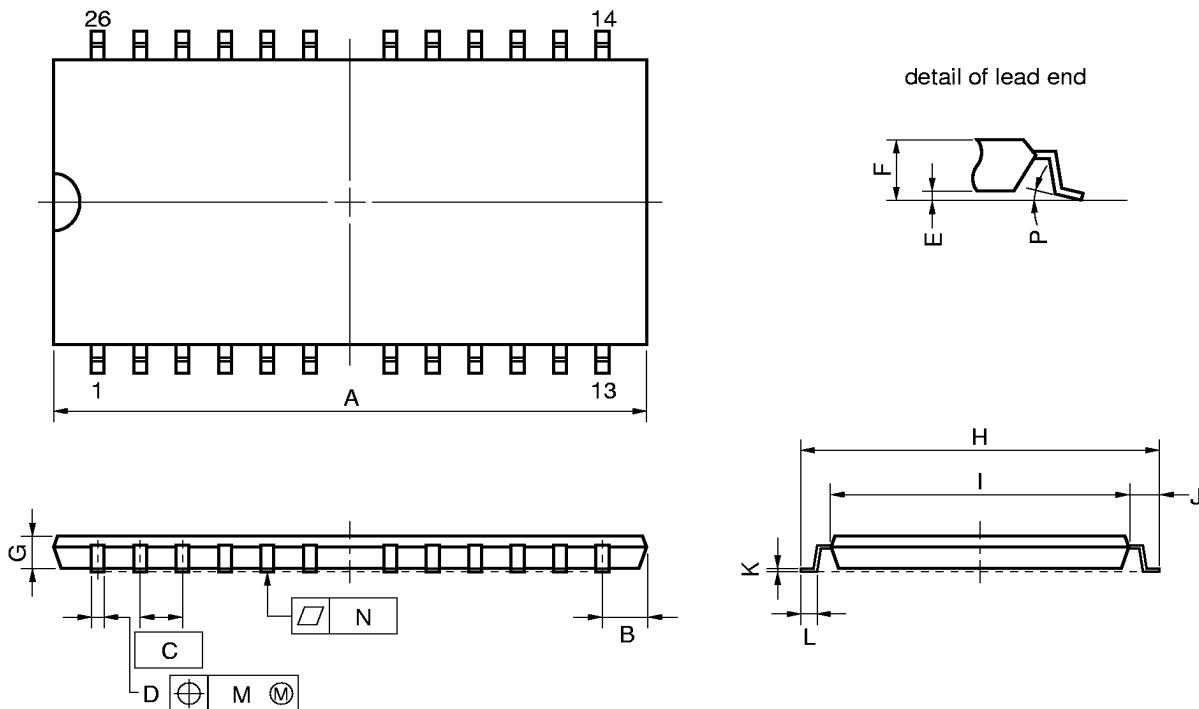
Refresh in the test mode must be performed with the \overline{RAS} / \overline{CAS} cycle or with the \overline{WE} , \overline{CAS} before \overline{RAS} refresh cycle. The \overline{WE} , \overline{CAS} before \overline{RAS} refresh cycle use the same counter as the \overline{CAS} before \overline{RAS} refresh's internal counter.

(4) Mode Cancellation

The test mode is cancelled by executing one cycle of \overline{RAS} only refresh cycle or \overline{CAS} before \overline{RAS} refresh cycle.

Package Drawings

26PIN PLASTIC TSOP(II) (300 mil)



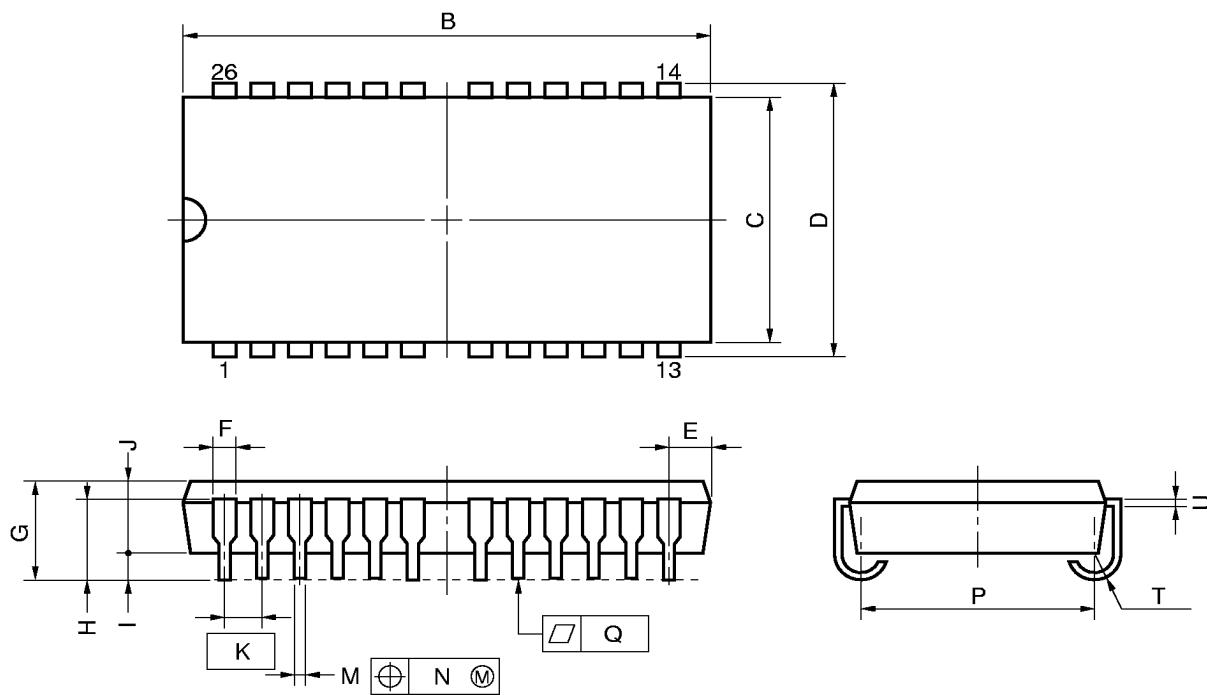
NOTE

Each lead centerline is located within 0.21 mm (0.009 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	17.36 MAX.	0.684 MAX.
B	1.06 MAX.	0.042 MAX.
C	1.27 (T.P.)	0.050 (T.P.)
D	0.42 ^{+0.08} _{-0.07}	0.017±0.003
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	0.97	0.038
H	9.22±0.2	0.363±0.008
I	7.62±0.1	0.300±0.004
J	0.8±0.2	0.031 ^{+0.009} _{-0.008}
K	0.145 ^{+0.025} _{-0.015}	0.006±0.001
L	0.5±0.1	0.020 ^{+0.004} _{-0.005}
M	0.21	0.009
N	0.10	0.004
P	3° ^{+7°} _{-3°}	3° ^{+7°} _{-3°}

S26G3-50-7JD1

26 PIN PLASTIC SOJ (300 mil)



NOTE

Each lead centerline is located within 0.12 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
B	$17.3^{+0.20}_{-0.25}$	$0.681^{+0.008}_{-0.010}$
C	7.62	0.300
D	8.47 ± 0.2	$0.333^{+0.009}_{-0.008}$
E	1.03 ± 0.15	$0.041^{+0.006}_{-0.007}$
F	0.74	0.029
G	3.5 ± 0.2	0.138 ± 0.008
H	2.545 ± 0.2	0.100 ± 0.008
I	0.8 MIN.	0.031 MIN.
J	2.6	0.102
K	1.27 (T.P.)	0.050 (T.P.)
M	0.40 ± 0.10	$0.016^{+0.004}_{-0.005}$
N	0.12	0.005
P	6.73 ± 0.2	0.265 ± 0.008
Q	0.10	0.004
T	R0.85	R0.033
U	$0.20^{+0.10}_{-0.05}$	$0.008^{+0.004}_{-0.002}$

S26LA-300A-1

★ Recommended Soldering Conditions

The following conditions (see tables below and next page) must be met for soldering conditions of the μ PD42S17405, 4217405.

For more details, refer to our document "SEMICONDUCTOR DEVICE MOUNTING TECHNOLOGY MANUAL" (C10535E).

Please consult with our sales offices in case other soldering process is used, or in case the soldering is done under different conditions.

Types of Surface Mount Device

μ PD42S17405G3-7JD, 4217405G3-7JD: 26-pin plastic TSOP (II) (300 mil)

Soldering process	Soldering conditions	Symbol
Infrared ray reflow	Peak temperature of package surface: 235 °C or lower, Reflow time: 30 seconds or less (210 °C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days ^{Note} (10 hours pre-baking is required at 125 °C afterwards)	IR35-107-3
VPS	Peak temperature of package: 215 °C or lower, Reflow time: 40 seconds or less (200 °C or higher), Number of reflow processes: MAX. 3 Exposure limit :7 days ^{Note} (10 hours pre-baking is required at 125 °C afterwards)	VP15-107-3
Partial heating method	Terminal temperature: 300 °C or lower, Time: 3 seconds or lower (Per side of the package).	—

Note Exposure limit before soldering after dry-pack package is opened.

Storage conditions: 25 °C and relative humidity at 65 % or less.

Caution Do not apply more than one soldering method at any one time, except for "Partial heating method".

μ PD42S17405LA, 4217405LA: 26-pin plastic SOJ (300 mil)

Soldering process	Soldering conditions	Symbol
Infrared ray reflow	Peak temperature of package surface: 235 °C or lower, Reflow time: 30 seconds or less (210 °C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days ^{Note} (20 hours pre-baking is required at 125 °C afterwards)	IR35-207-3
VPS	Peak temperature of package: 215 °C or lower, Reflow time: 40 seconds or less (200 °C or higher), Number of reflow processes: MAX. 3 Exposure limit: 7 days ^{Note} (20 hours pre-baking is required at 125 °C afterwards)	VP15-207-3
Partial heating method	Terminal temperature: 300 °C or lower, Time: 3 seconds or less (Per side of the package).	—

Note Exposure limit before soldering after dry-pack package is opened.

Storage conditions: 25 °C and relative humidity at 65 % or less.

Caution Do not apply more than one soldering method at any one time, except for "Partial heating method".